VNQ600P

QUAD CHANNEL HIGH SIDE DRIVER

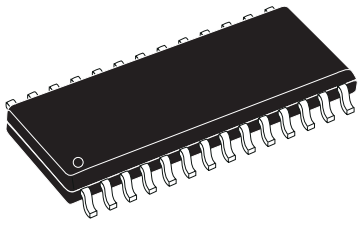
Table 1. General Features

TYPE	$R_{DS(on)}$ (*)	I_{lim}	V_{CC}
VNQ600P	35mΩ	25A	36 V

(*) Per each channel

- DC SHORT CIRCUIT CURRENT: 22A
- CMOS COMPATIBLE INPUTS
- PROPORTIONAL LOAD CURRENT SENSE
- UNDERVOLTAGE & OVERVOLTAGE SHUT-DOWN
- OVERVOLTAGE CLAMP
- THERMAL SHUT-DOWN
- CURRENT LIMITATION
- VERY LOW STAND-BY POWER DISSIPATION
- PROTECTION AGAINST: LOSS OF GROUND & LOSS OF V_{CC}
- REVERSE BATTERY PROTECTION (**)

Figure 1. Package



SO-28 (DOUBLE ISLAND)

DESCRIPTION

The VNQ600P is a quad HSD formed by assembling two VND600 chips in the same SO-28 package. The VND600 is a monolithic device designed in STMicroelectronics VIPower M0-3 Technology.

The VNQ600P is intended for driving any type of multiple loads with one side connected to ground. This device has four independent channels and four analog sense outputs which deliver currents proportional to the outputs currents. Active current limitation combined with thermal shut-down and automatic restart protect the device against overload. Device automatically turns off in case of ground pin disconnection.

Table 2. Order Codes

Package	Tube	Tape and Reel
SO-28	VNQ600P	VNQ600P13TR

Note: (**) See application schematic at page 11.

Figure 2. Block Diagram

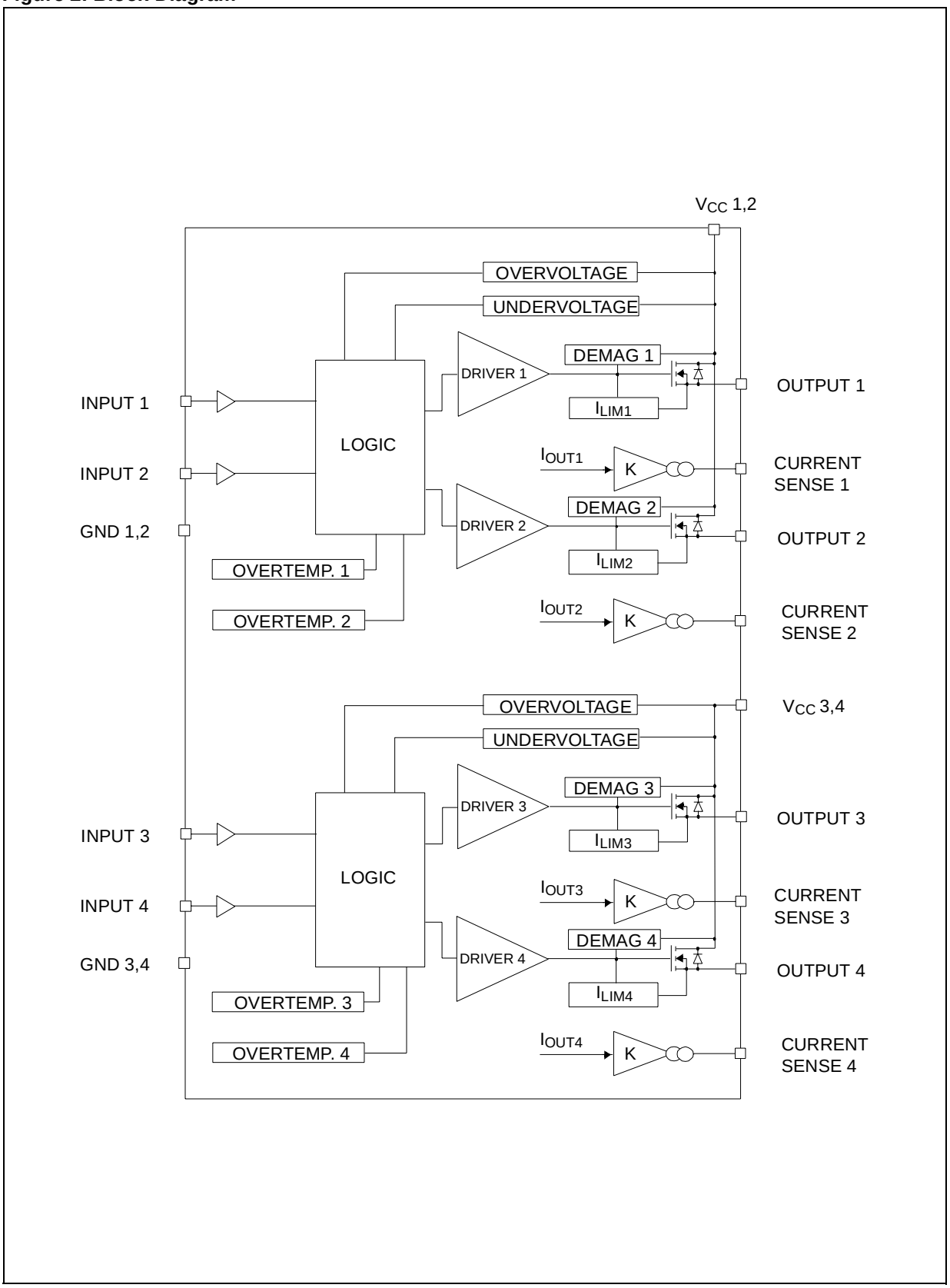
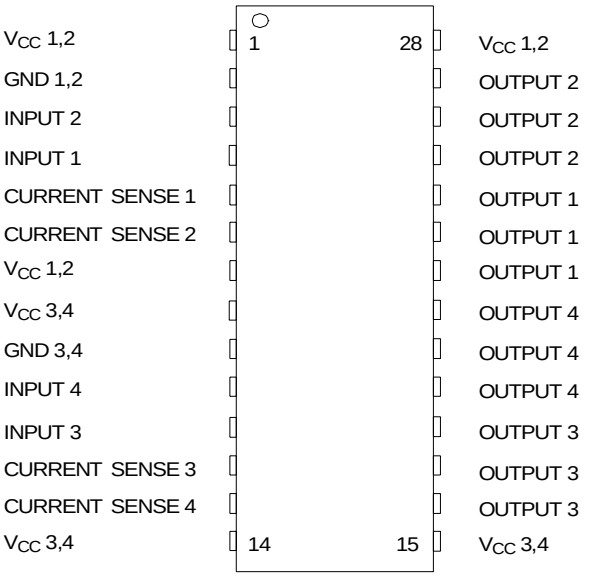


Table 3. Absolute Maximum Ratings

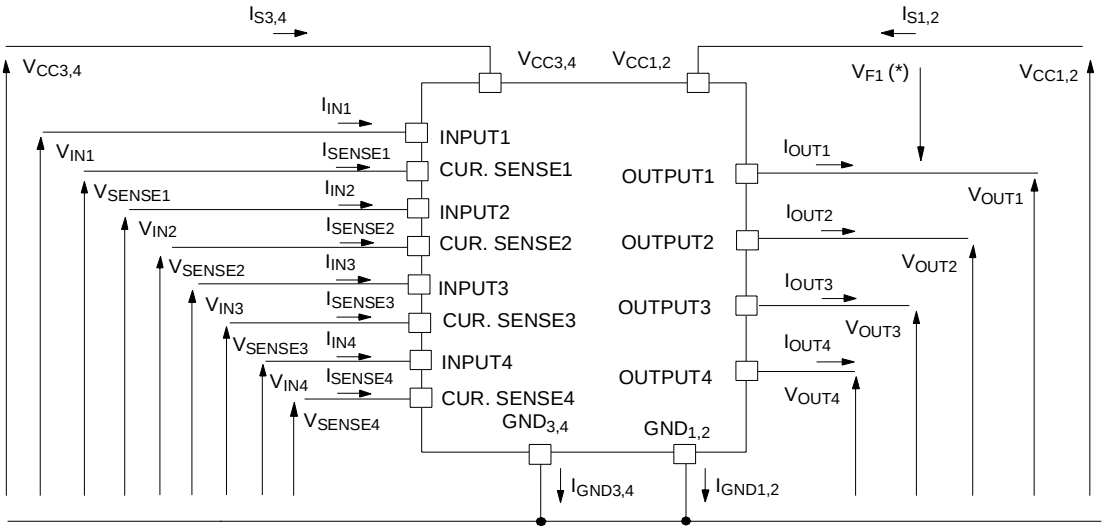
Symbol	Parameter	Value	Unit
V_{CC}	Supply voltage (continuous)	41	V
$-V_{CC}$	Reverse supply voltage (continuous)	-0.3	V
I_{OUT}	Output current (continuous), for each channel	15	A
I_R	Reverse output current (continuous), for each channel	-15	A
I_{IN}	Input current	+/- 10	mA
V_{CSENSE}	Current sense maximum voltage	-3 +15	V V
I_{GND}	Ground current at $T_{pins} \leq 25°C$ (continuous)	-200	mA
V_{ESD}	Electrostatic Discharge (Human Body Model: R=1.5KΩ; C=100pF) - INPUT - CURRENT SENSE - OUTPUT - V_{CC}	 4000 2000 5000 5000	 V V V V
E_{MAX}	Maximum Switching Energy (L=0.11mH; R_L=0Ω; V_{bat}=13.5V; T_{jstart}=150ºC; I_L=40A)	126	mJ
P_{tot}	Power dissipation (per island) at T_{lead}=25°C	6.25	W
T_j	Junction operating temperature	Internally Limited	°C
T_{stg}	Storage temperature	-55 to 150	°C

Figure 3. Configuration Diagram (Top View) & Suggested Connections for Unused and N.C. Pins



Connection / Pin	Current Sense	N.C.	Output	Input
Floating		X	X	X
To Ground	Through 1KΩ resistor	X		Through 10KΩ resistor

Figure 4. Current and Voltage Conventions



(*) $V_{Fn} = V_{CCn} - V_{OUTn}$ during reverse battery condition

Table 4. Thermal Data

Symbol	Parameter		Value		Unit
$R_{thj\text{-}case}$	Thermal resistance junction-case	(MAX)	15		°C/W
$R_{thj\text{-}amb}$	Thermal resistance junction-ambient (one chip ON)	(MAX)	60 (1)	44 (2)	°C/W
$R_{thj\text{-}amb}$	Thermal resistance junction-ambient (two chips ON)	(MAX)	46 (1)	31 (2)	°C/W

Note: 1. When mounted on a standard single-sided FR-4 board with 0.5cm^2 of Cu (at least 35µm thick) connected to all V_{CC} pins. Horizontal mounting and no artificial air flow.

Note: 2. When mounted on a standard single-sided FR-4 board with 6cm^2 of Cu (at least 35µm thick) connected to all V_{CC} pins. Horizontal mounting and no artificial air flow.

ELECTRICAL CHARACTERISTICS (8V<V_{CC}<36V; -40°C<T_j<150°C unless otherwise specified)

(Per each channel)

Table 5. Power

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
V_{CC} (**)	Operating supply voltage		5.5	13	36	V
V_{USD} (**)	Undervoltage shut-down		3	4	5.5	V
V_{OV} (**)	Overvoltage shut-down		36			V
R_{ON}	On state resistance	I_{OUT}1,2,3,4=5A; T_j=25°C I_{OUT}1,2,3,4=5A; T_j=150°C I_{OUT}1,2,3,4=3A; V_{CC}=6V			35 70 120	mΩ mΩ mΩ
V_{clamp}	Clamp Voltage	I_{CC}=20mA (see note 3)	41	48	55	V
I_S (**)	Supply current	Off State; V_{CC}=13V; V_{IN}=V_{OUT}=0V Off State; V_{CC}=13V; V_{IN}=V_{OUT}=0V; T_j =25°C On State; V_{CC}=13V; V_{IN}=5V; I_{OUT}=0A; R_{SENSE}=3.9KΩ		12 12	40 25 6	µA µA mA
$I_{L(off1)}$	Off state output current	V_{IN}=V_{OUT}=0V	0		50	µA
$I_{L(off2)}$	Off State Output Current	V_{IN}=0V; V_{OUT}=3.5V	-75		0	µA
$I_{L(off3)}$	Off State Output Current	V_{IN}=V_{OUT}=0V; V_{CC}=13V; T_j =125°C			5	µA
$I_{L(off4)}$	Off State Output Current	V_{IN}=V_{OUT}=0V; V_{CC}=13V; T_j =25°C			3	µA

Note: 3. V_{clamp} and V_{OV} are correlated. Typical difference is 5V.
Note: (**) Per island.

Table 6. Switching (V_{CC} =13V)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	R_L=2.6Ω channels 1,2,3,4 (see fig. 1)		40		µs
$t_{d(off)}$	Turn-off delay time	R_L=2.6Ω channels 1,2,3,4 (see fig. 1)		40		µs
$(dV_{OUT}/dt)_{on}$	Turn-on voltage slope	R_L=2.6Ω channels 1,2,3,4 (see fig. 1)		See relative diagram		V/µs
$(dV_{OUT}/dt)_{off}$	Turn-off voltage slope	R_L=2.6Ω channels 1,2,3,4 (see fig. 1)		See relative diagram		V/µs

Table 7. V_{CC} - Output Diode

Symbol	Parameter	Test Conditions	Min	Typ	Max	Unit
V_F	Forward on Voltage	-I_{OUT}=2.3A; T_j=150°C			0.6	V

ELECTRICAL CHARACTERISTICS (continued)

Table 8. Logic Input

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
V_{IL}	Low level input voltage				1.25	V
V_{IH}	High level input voltage		3.25			V
$V_{I(hyst)}$	Input hysteresis voltage		0.5			V
I_{IL}	Input current	V_{IN}=1.5V	1			µA
I_{IN}	Input current	V_{IN}=3.5V			10	µA
V_{ICL}	Input clamp voltage	I_{IN}=1mA I_{IN}= -1mA	6	6.8 -0.7	8	V V

Table 9. Protections (See note 4)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
I_{lim}	DC Short circuit current	V_{CC}=13V 5.5V<V_{CC}<36V	25	40	70 70	A A
T_{TSD}	Thermal shut-down temperature		150	175	200	°C
T_R	Thermal reset temperature		135			°C
T_{hyst}	Thermal hysteresis		7	15		°C
V_{demag}	Turn-off output voltage clamp	I_{OUT}=2A; L=6mH	V_{CC}-41	V_{CC}-48	V_{CC}-55	V
V_{ON}	Output voltage drop limitation	I_{OUT}=0.5A; T_j= -40°C...+150°C		50		mV

Note: 4. To ensure long term reliability under heavy overload or short circuit conditions, protection and related diagnostic signals must be used together with a proper software strategy. If the device is subjected to abnormal conditions, this software must limit the duration and number of activation cycles.

ELECTRICAL CHARACTERISTICS (continued)

Table 10. CURRENT SENSE (9V ≤ VCC ≤ 16V) (See Figure 5)

Symbol	Parameter	Test Conditions	Min	Typ	Max	Unit
K_1	I_{OUT}/I_{SENSE}	I_{OUT1} or I_{OUT2}=0.5A; V_{SENSE}=0.5V; other channels open; T_j= -40°C...150°C	3300	4400	6000	
dK_1/K_1	Current Sense Ratio Drift	I_{OUT1} or I_{OUT2}=0.5A; V_{SENSE}=0.5V; other channels open; T_j= -40°C...150°C	-10		+10	%
K_2	I_{OUT}/I_{SENSE}	I_{OUT1} or I_{OUT2}=5A; V_{SENSE}=4V; other channels open; T_j=-40°C T_j=25°C...150°C	4200 4400	4900 4900	6000 5750	
dK_2/K_2	Current Sense Ratio Drift	I_{OUT1} or I_{OUT2}=5A; V_{SENSE}=4V; other channels open; T_j=-40°C...150°C	-6		+6	%
K_3	I_{OUT}/I_{SENSE}	I_{OUT1} or I_{OUT2}=15A; V_{SENSE}=4V; other channels open; T_j=-40°C T_j=25°C...150°C	4200 4400	4900 4900	5500 5250	
dK_3/K_3	Current Sense Ratio Drift	I_{OUT1} or I_{OUT2}=15A; V_{SENSE}=4V; other channels open; T_j=-40°C...150°C	-6		+6	%
$V_{SENSE1,2}$	Max analog sense output voltage	V_{CC}=5.5V; $I_{OUT1,2}$=2.5A; R_{SENSE}=10kΩ V_{CC}>8V, $I_{OUT1,2}$=5A; R_{SENSE}=10kΩ	2 4			V V
V_{SENSEH}	Analog sense output voltage in overtemperature condition	V_{CC}=13V; R_{SENSE}=3.9kΩ		5.5		V
$R_{VSENSEH}$	Analog Sense Output Impedance in Overtemperature Condition	V_{CC}=13V; T_j>T_{TSD}; All channels open		400		Ω
t_{DSENSE}	Current sense delay response	to 90% I_{SENSE} (see note 5)			500	µs

Note: 5. Current sense signal delay after positive input slope.

Figure 5. I_{OUT}/I_{SENSE} **versus** I_{OUT}

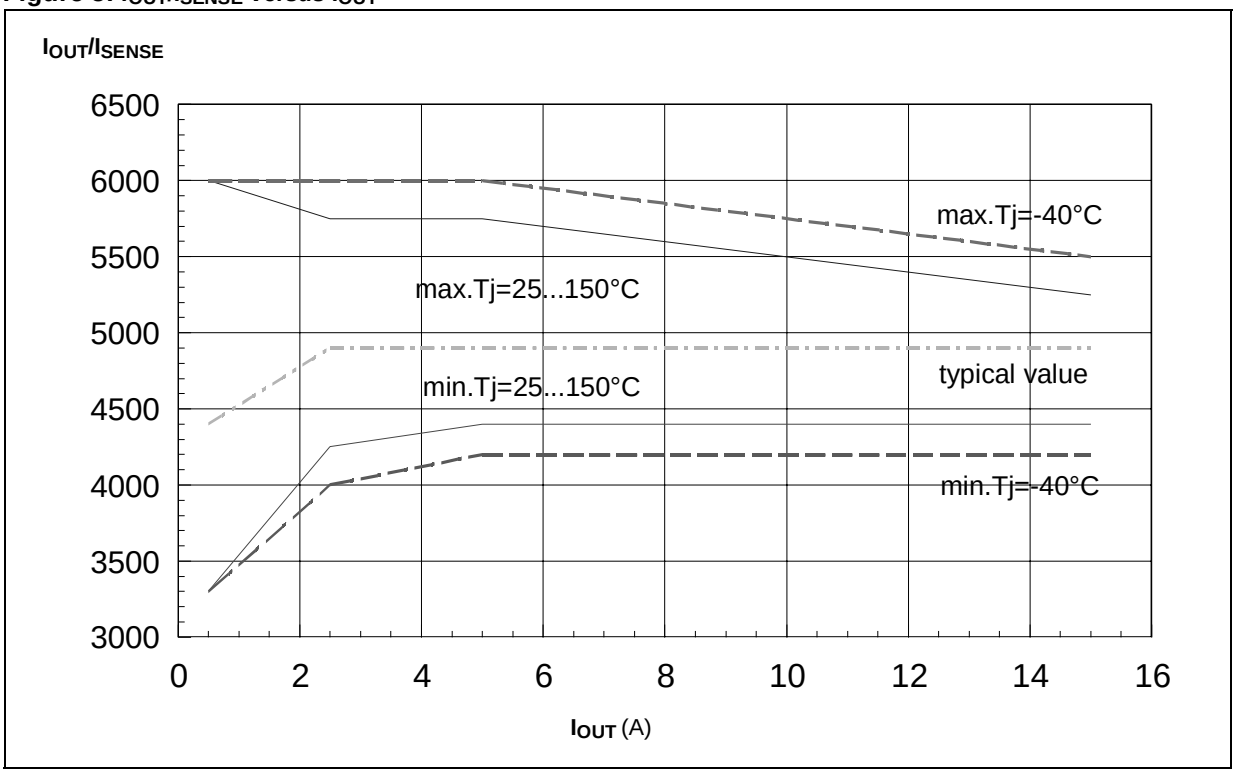


Figure 6. Switching Characteristics (Resistive load R_L=2.6Ω)

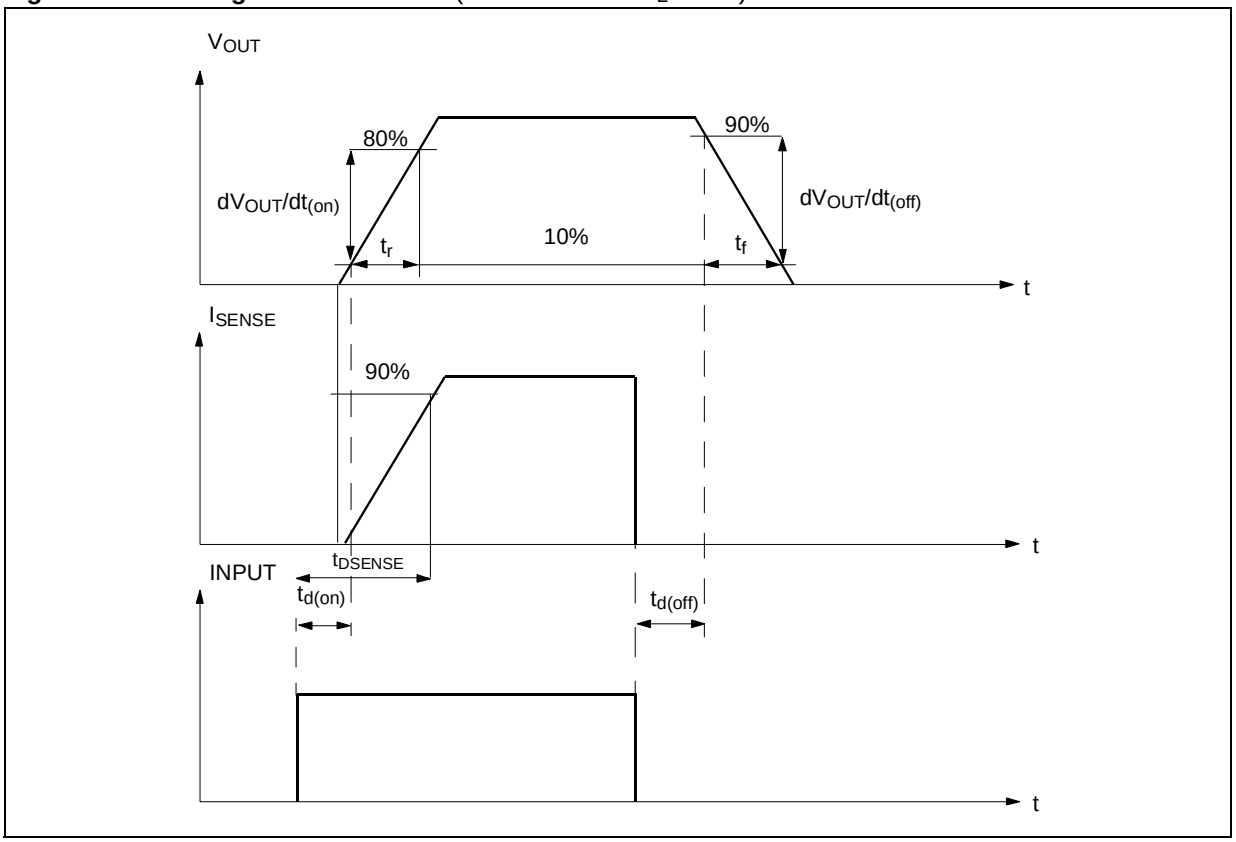


Table 11. Truth Table (Per channel)

CONDITIONS	INPUT	OUTPUT	SENSE
Normal operation	L H	L H	0 Nominal
Overtemperature	L H	L L	0 V_{SENSEH}
Undervoltage	L H	L L	0 0
Overvoltage	L H	L L	0 0
Short circuit to GND	L H H	L L L	0 (T_j<T_{TSD}) 0 (T_j>T_{TSD}) V_{SENSEH}
Short circuit to V_{CC}	L H	H H	0 < Nominal
Negative output voltage clamp	L	L	0

Table 12. Electrical Transient Requirements on V_{CC} Pin

ISO T/R 7637/1 Test Pulse	TEST LEVELS				
	I	II	III	IV	Delays and Impedance
1	-25 V	-50 V	-75 V	-100 V	2 ms 10 Ω
2	+25 V	+50 V	+75 V	+100 V	0.2 ms 10 Ω
3a	-25 V	-50 V	-100 V	-150 V	0.1 µs 50 Ω
3b	+25 V	+50 V	+75 V	+100 V	0.1 µs 50 Ω
4	-4 V	-5 V	-6 V	-7 V	100 ms, 0.01 Ω
5	+26.5 V	+46.5 V	+66.5 V	+86.5 V	400 ms, 2 Ω

ISO T/R 7637/1 Test Pulse	TEST LEVELS RESULTS			
	I	II	III	IV
1	C	C	C	C
2	C	C	C	C
3a	C	C	C	C
3b	C	C	C	C
4	C	C	C	C
5	C	E	E	E

CLASS	CONTENTS
C	All functions of the device are performed as designed after exposure to disturbance.
E	One or more functions of the device is not performed as designed after exposure to disturbance and cannot be returned to proper operation without replacing the device.

Figure 7. Waveforms (Per each chip)

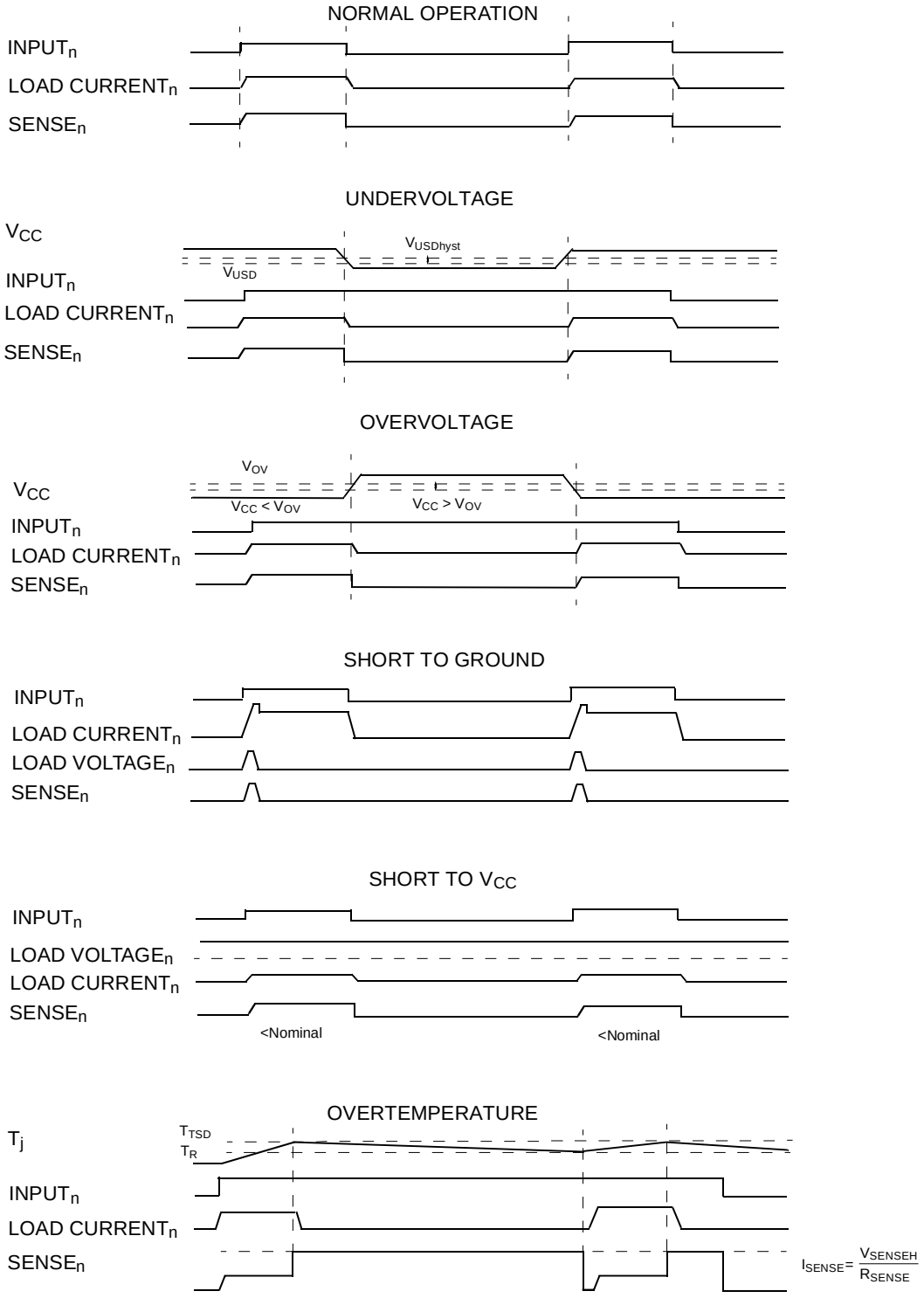
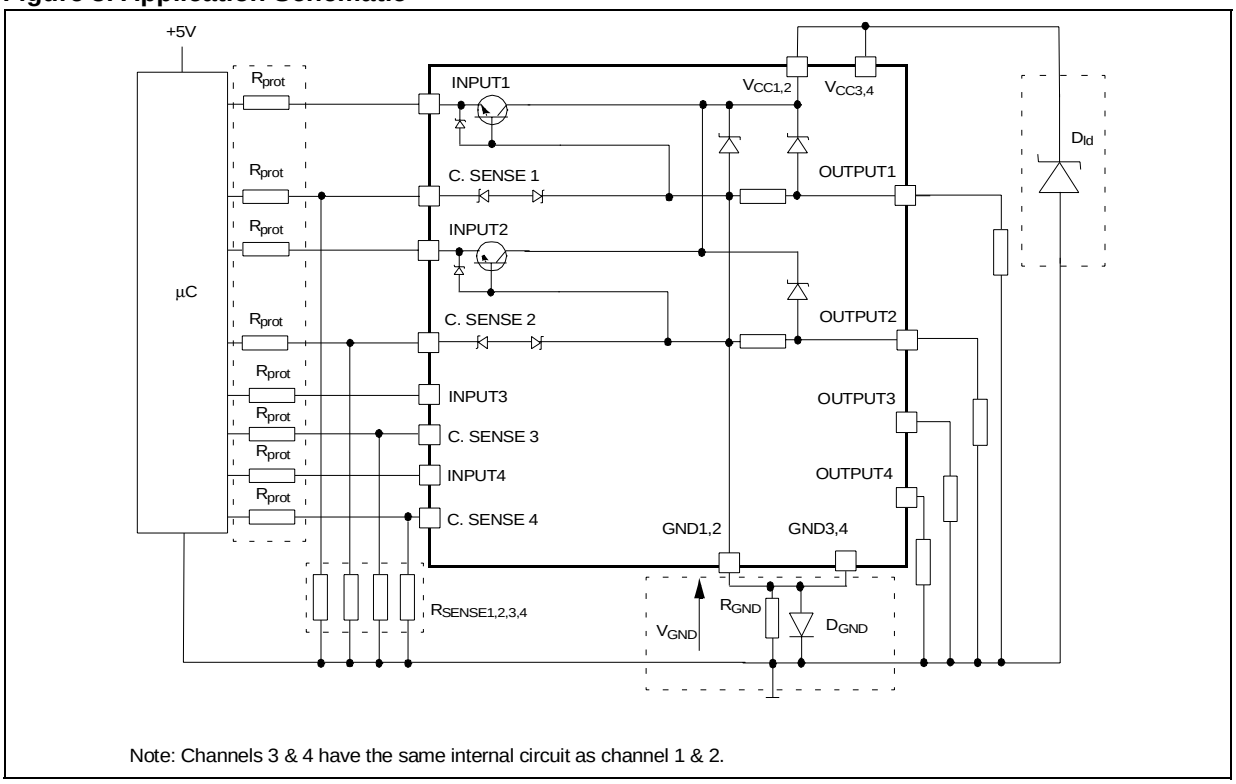


Figure 8. Application Schematic



Note: Channels 3 & 4 have the same internal circuit as channel 1 & 2.

GND PROTECTION NETWORK AGAINST REVERSE BATTERY

Solution 1: Resistor in the ground line (R_{GND} only). This can be used with any type of load.

The following is an indication on how to dimension the R_{GND} resistor.

1) $R_{GND} \leq 600mV / 2(I_{S(on)max})$.

2) $R_{GND} \geq (-V_{CC}) / (-I_{GND})$

where $-I_{GND}$ is the DC reverse ground pin current and can be found in the absolute maximum rating section of the device's datasheet.

Power Dissipation in R_{GND} (when $V_{CC}<0$: during reverse battery situations) is:

$P_D= (-V_{CC})^2/R_{GND}$

This resistor can be shared amongst several different HSD. Please note that the value of this resistor should be calculated with formula (1) where $I_{S(on)max}$ becomes the sum of the maximum on-state currents of the different devices.

Please note that if the microprocessor ground is not common with the device ground then the R_{GND} will produce a shift ($I_{S(on)max} * R_{GND}$) in the input thresholds and the status output values. This shift will vary depending on how many devices are ON in the case of several high side drivers sharing the same R_{GND}.

If the calculated power dissipation leads to a large resistor or several devices have to share the same resistor then the ST suggests to utilize Solution 2 (see below).

Solution 2: A diode (D_{GND}) in the ground line.

A resistor (R_{GND}=1kΩ) should be inserted in parallel to D_{GND} if the device will be driving an inductive load.

This small signal diode can be safely shared amongst several different HSD. Also in this case, the presence of the ground network will produce a shift (j600mV) in the input threshold and the status output values if the microprocessor ground is not common with the device ground. This shift will not vary if more than one HSD shares the same diode/resistor network.

Series resistor in INPUT line is also required to prevent that, during battery voltage transient, the current exceeds the Absolute Maximum Rating.

Safest configuration for unused INPUT pin is to leave it unconnected, while unused SENSE pin has to be connected to Ground pin.

LOAD DUMP PROTECTION

D_{ld} is necessary (Voltage Transient Suppressor) if the load dump peak voltage exceeds V_{CC} max DC rating. The same applies if the device will be subject to transients on the V_{CC} line that are greater than the ones shown in the ISO T/R 7637/1 table.

µC I/Os PROTECTION:

If a ground protection network is used and negative transients are present on the V_{CC} line, the control pins will be pulled negative. ST suggests to insert a resistor (R_{prot}) in line to prevent the µC I/Os pins to latch-up.

The value of these resistors is a compromise between the leakage current of µC and the current required by the HSD I/Os (Input levels compatibility) with the latch-up limit of µC I/Os.

$-V_{CCpeak}/I_{latchup} \leq R_{prot} \leq (V_{OH\mu C}-V_{IH}-V_{GND}) / I_{IHmax}$

Calculation example:

For V_{CCpeak}= - 100V and $I_{latchup} \geq$ 20mA; $V_{OH\mu C} \geq$ 4.5V

5kΩ ≤ R_{prot} ≤ 65kΩ.

Recommended R_{prot} value is 10kΩ.

Figure 9. Off State Output Current

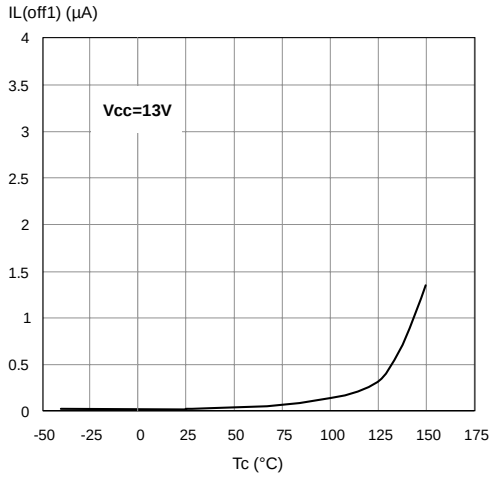


Figure 10. Low Level Input Current

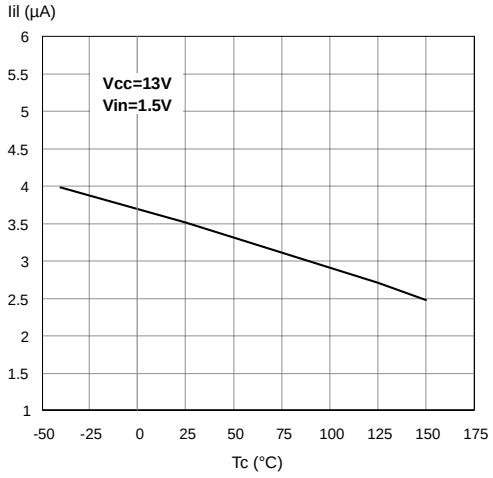


Figure 11. Input Clamp Voltage

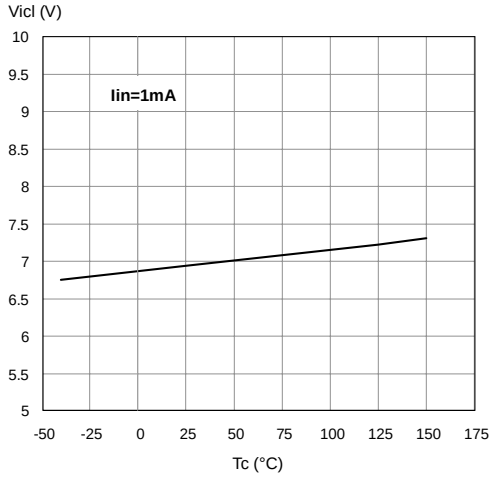


Figure 13. Input High Level

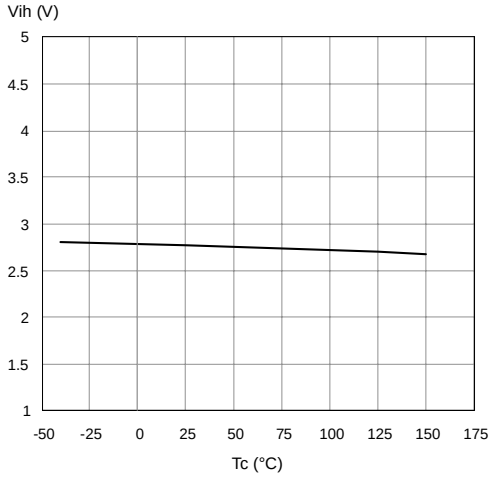


Figure 12. Input Low Level

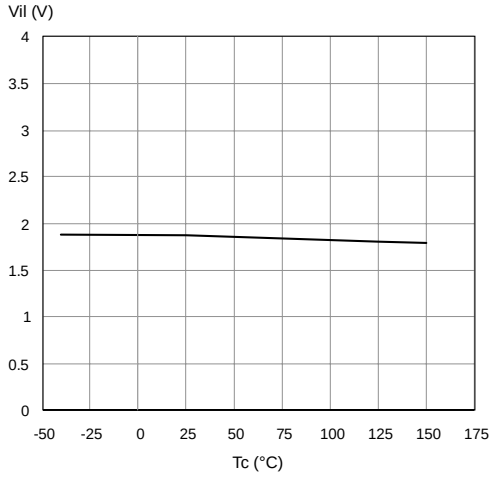


Figure 14. Input Hysteresis Voltage

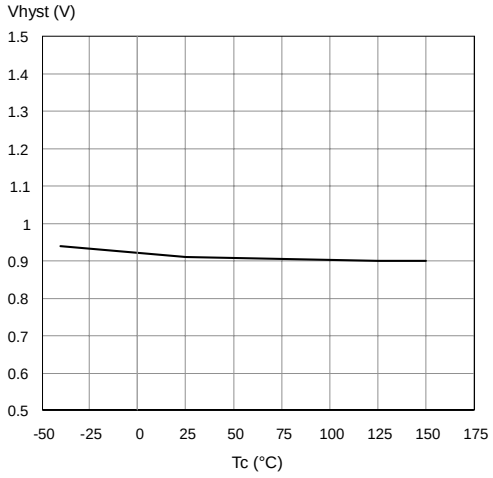


Figure 15. Overvoltage Shutdown

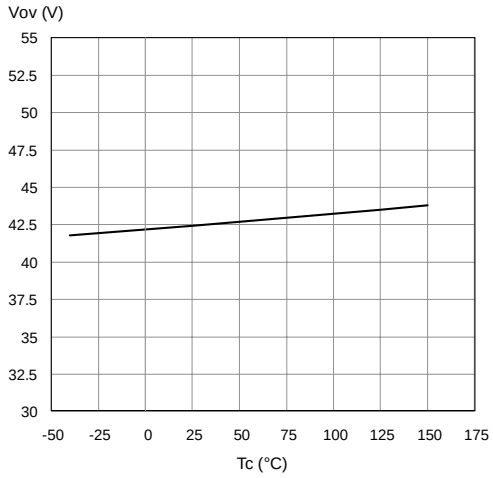


Figure 16. I_{LIM} Vs T_{case}

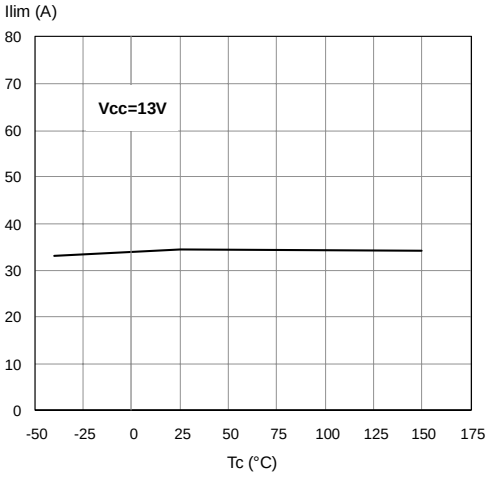


Figure 17. Turn-on Voltage Slope

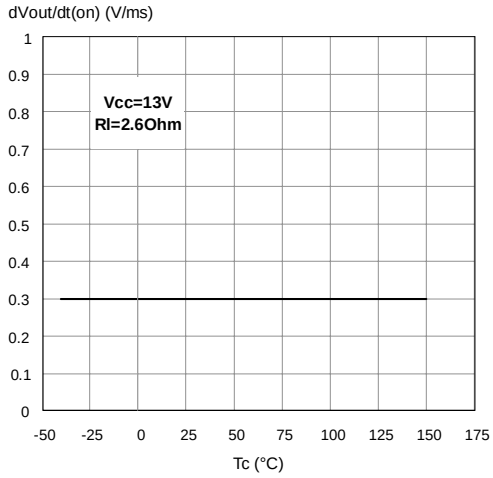


Figure 19. Turn-off Voltage Slope

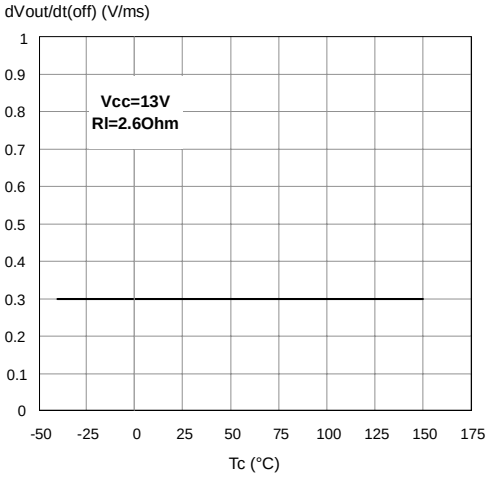


Figure 18. On State Resistance Vs T_{case}

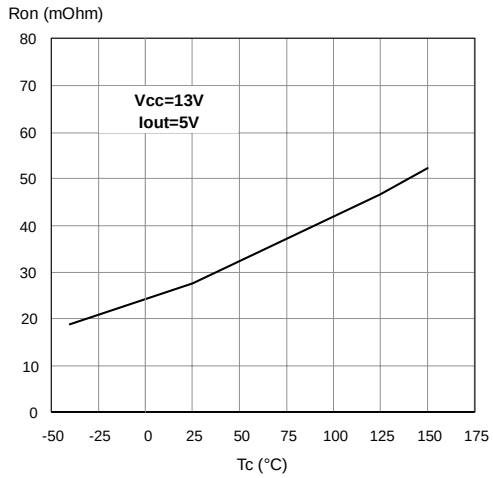
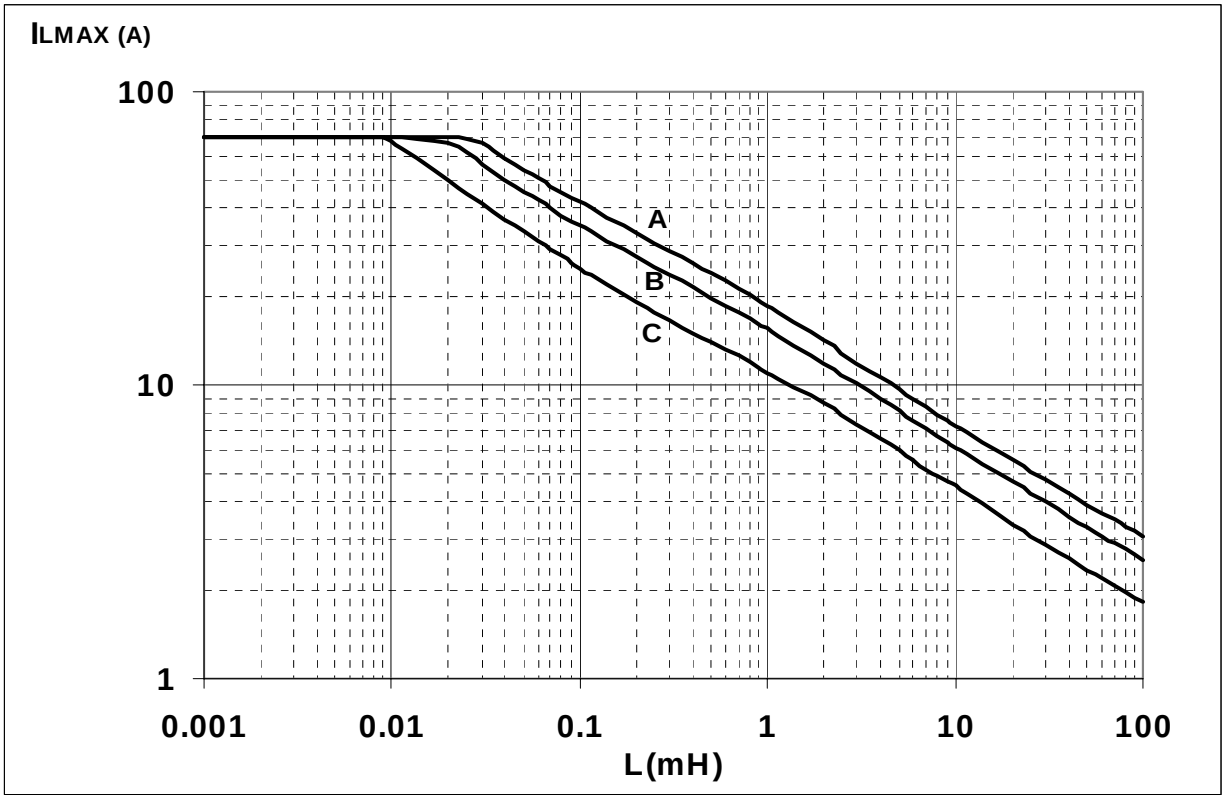


Figure 20. Maximum Turn Off Current Versus Load Inductance



A = Single Pulse at T_{Jstart}=150ºC

B= Repetitive pulse at T_{Jstart}=100ºC

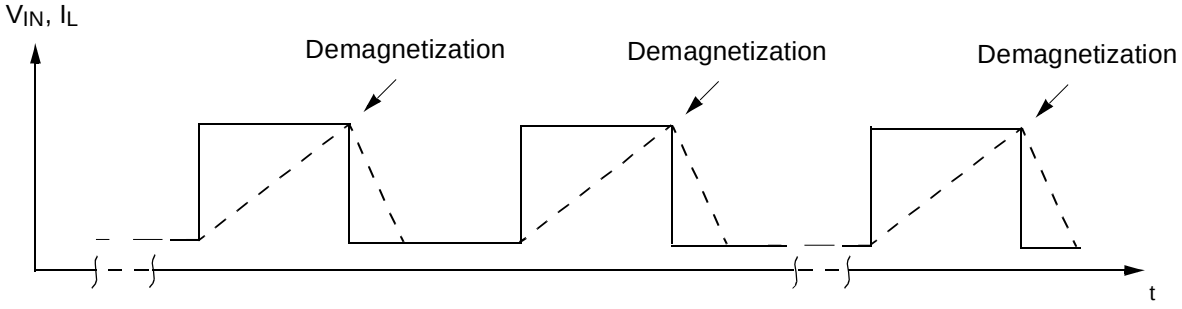
C= Repetitive Pulse at T_{Jstart}=125ºC

Conditions:

V_{CC}=13.5V

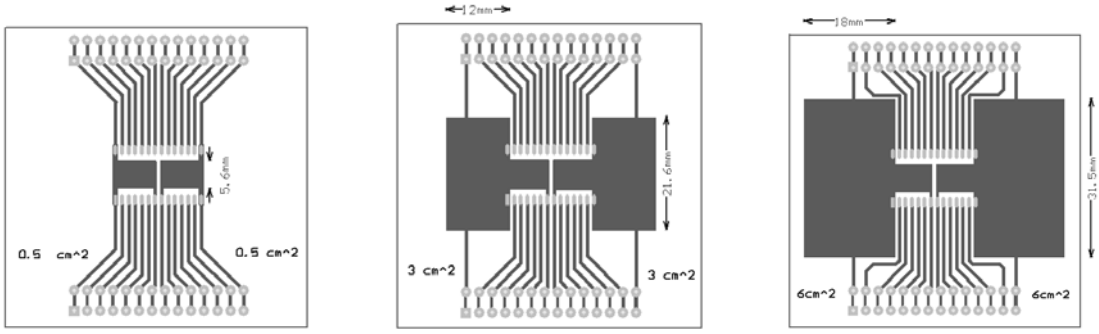
Values are generated with R_L=0Ω

In case of repetitive pulses, T_{jstart} (at beginning of each demagnetization) of every pulse must not exceed the temperature specified above for curves B and C.



SO-28 Thermal Data

Figure 21. SO-28 Double Island PC Board



Layout condition of R_{th} and Z_{th} measurements (PCB FR4 area= 58mm x 58mm, PCB thickness=2mm, Cu thickness=35µm, Copper areas: 0.5cm^2, 3cm^2, 6cm^2).

Table 13. Thermal Calculation According to the PCB Heatsink Area

Chip 1	Chip 2	T_{jchip1}	T_{jchip2}	Note
ON	OFF	R_{thA} x P_{dchip1} + T_{amb}	R_{thC} x P_{dchip1} + T_{amb}	
OFF	ON	R_{thC} x P_{dchip2} + T_{amb}	R_{thA} x P_{dchip2} + T_{amb}	
ON	ON	R_{thB} x (P_{dchip1} + P_{dchip2}) + T_{amb}	R_{thB} x (P_{dchip1} + P_{dchip2}) + T_{amb}	P_{dchip1}=P_{dchip2}
ON	ON	(R_{thA} x P_{dchip1}) + R_{thC} x P_{dchip2} + T_{amb}	(R_{thA} x P_{dchip2}) + R_{thC} x P_{dchip1} + T_{amb}	P_{dchip1}≠P_{dchip2}

Note: R_{thA} = Thermal resistance Junction to Ambient with one chip ON
Note: R_{thB} = Thermal resistance Junction to Ambient with both chips ON and P_{dchip1}=P_{dchip2}
Note: R_{thC} = Mutual thermal resistance

Figure 22. $R_{thj\text{-}amb}$ Vs PCB Copper Area In Open Box Free Air Condition

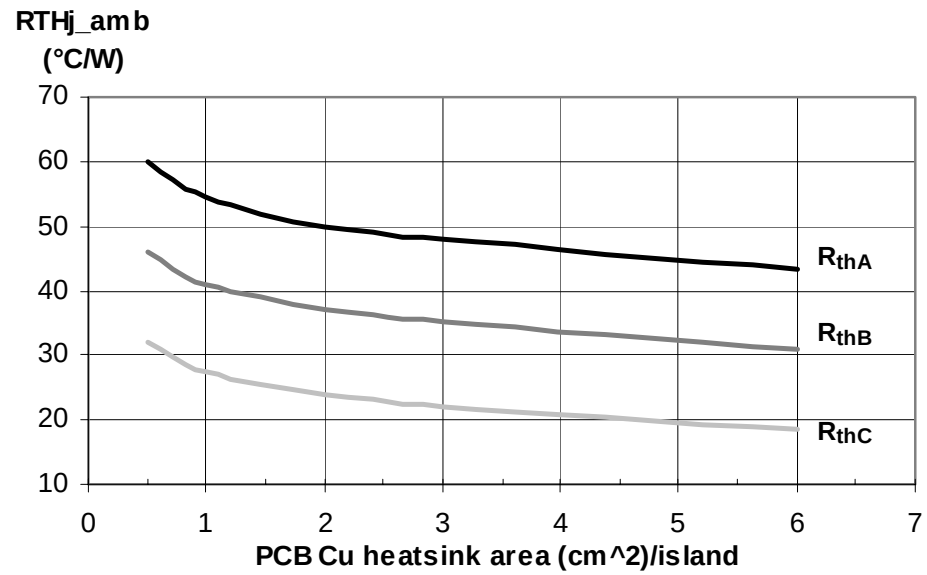


Figure 23. SO-28 Thermal Impedance Junction Ambient Single Pulse

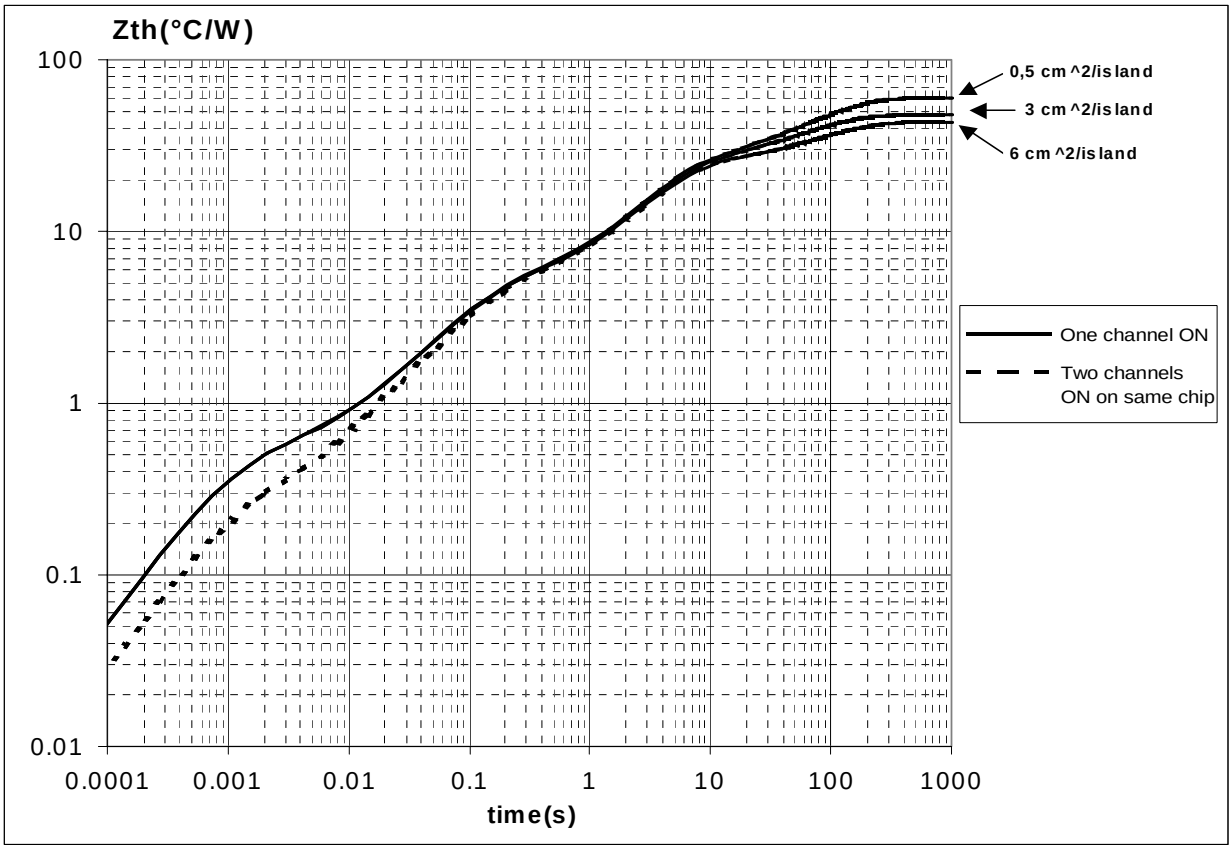
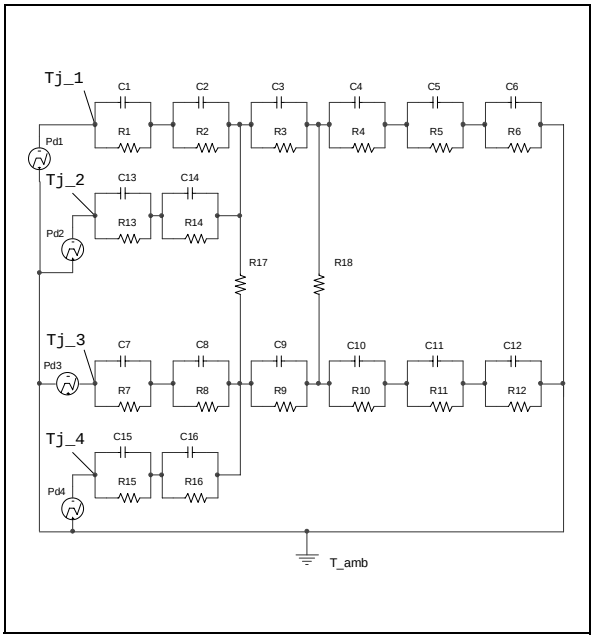


Figure 24. Thermal Fitting Model Of A Quad Channels HSD in SO-28



Pulse Calculation Formula

$$Z_{TH\delta} = R_{TH} \cdot \delta + Z_{THtp}(1 - \delta)$$

where $\delta = t_p / T$

Table 14. Thermal Parameter

Area/island (cm^2)	0.5	6
R1=R7=R13=R15 (°C/W)	0.05	
R2=R8=R14=R16 (°C/W)	0.3	
R3=R9 (°C/W)	3.4	
R4=R10 (°C/W)	11	
R5=R11 (°C/W)	15	
R6=R12 (°C/W)	30	13
C1=C7=C13=C15 (W.s/°C)	0.001	
C2=C8=C14=C16 (W.s/°C)	5.00E-03	
C3=C9 (W.s/°C)	1.00E-02	
C4=C10 (W.s/°C)	0.2	
C5=C11 (W.s/°C)	1.5	
C6=C12 (W.s/°C)	5	8
R17=R18 (°C/W)	150	

PACKAGE MECHANICAL

Table 15. SO-28 Mechanical Data

Symbol	millimeters		
	Min	Typ	Max
A			2.65
a1	0.10		0.30
b	0.35		0.49
b1	0.23		0.32
C		0.50	
c1	45 (typ.)		
D	17.7		18.1
E	10.00		10.65
e		1.27	
e3		16.51	
F	7.40		7.60
L	0.40		1.27
S	8 (max.)		

Figure 25. SO-28 Package Dimensions

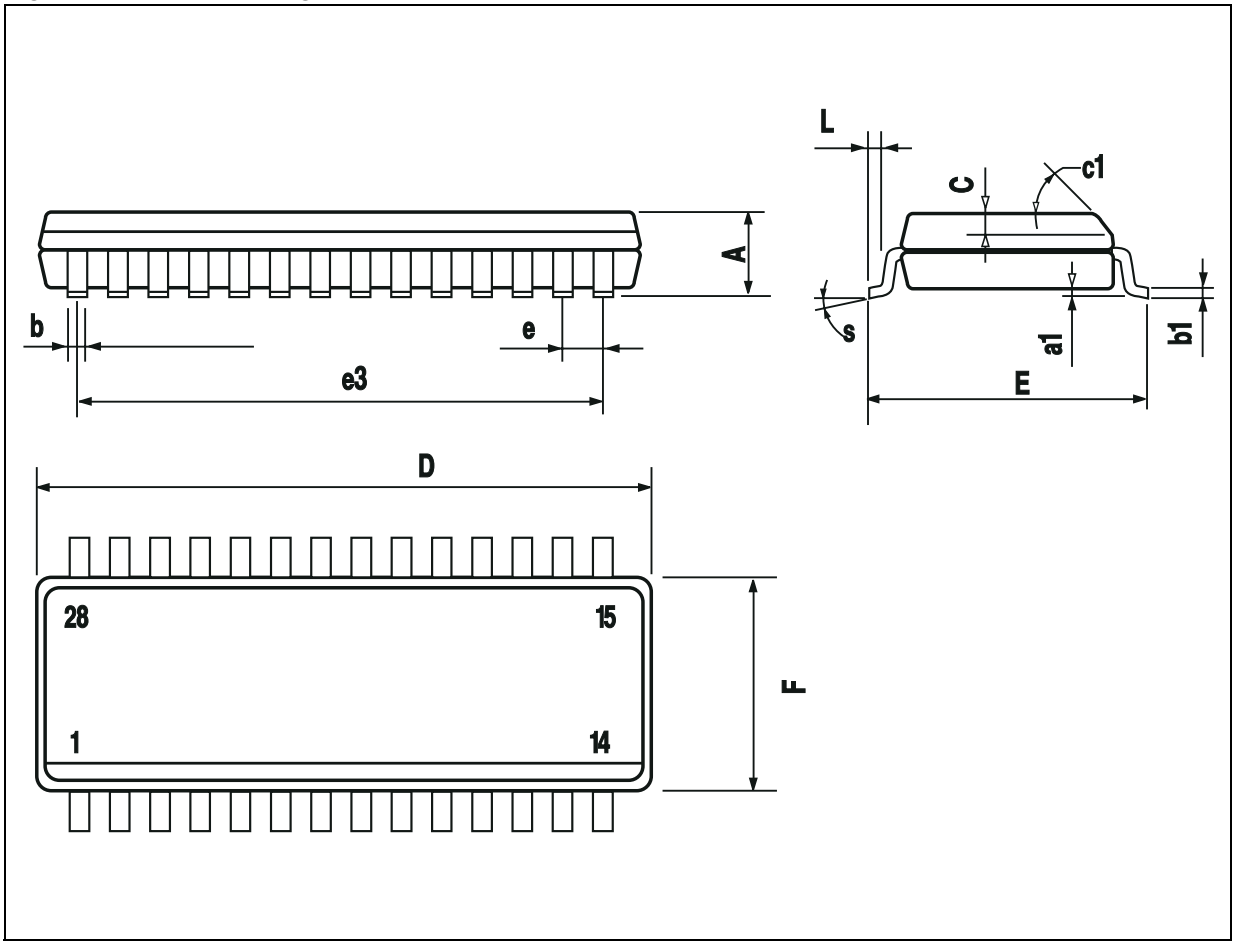
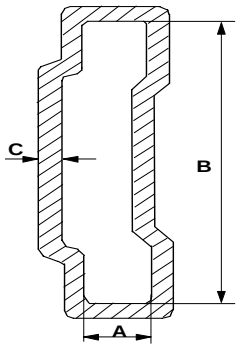


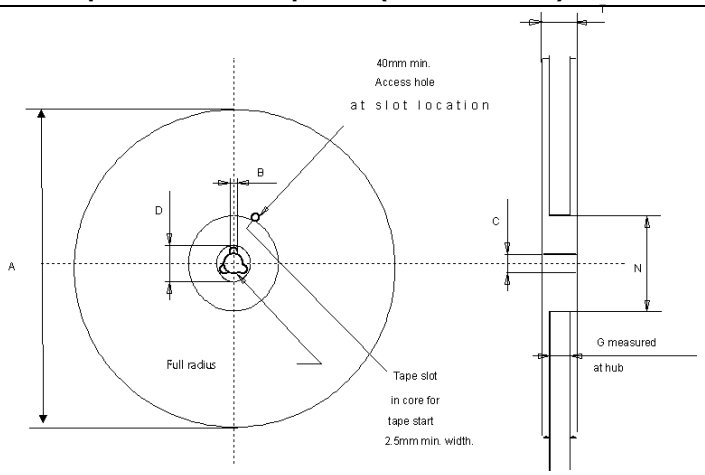
Figure 26. SO-28 Tube Shipment (no suffix)



Base Q.ty	28
Bulk Q.ty	700
Tube length (± 0.5)	532
A	3.5
B	13.8
C (± 0.1)	0.6

All dimensions are in mm.

Figure 27. Tape And Reel Shipment (suffix "13TR")



REEL DIMENSIONS

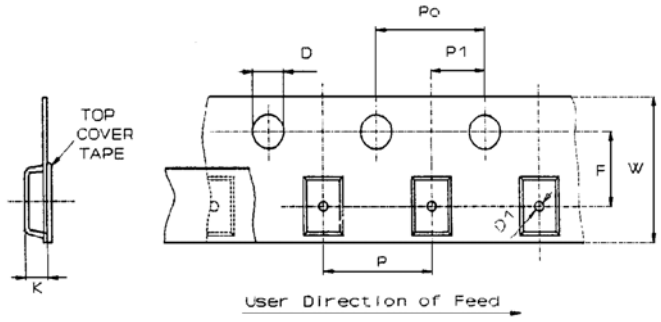
Base Q.ty	1000
Bulk Q.ty	1000
A (max)	330
B (min)	1.5
C (± 0.2)	13
F	20.2
G (+ 2 / -0)	16.4
N (min)	60
T (max)	22.4

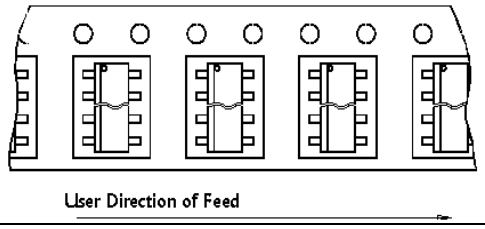
TAPE DIMENSIONS

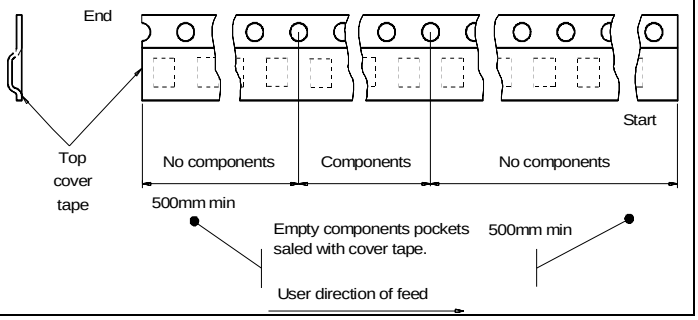
According to Electronic Industries Association (EIA) Standard 481 rev. A, Feb 1986

Tape width	**W**	16
Tape Hole Spacing	**P0 (± 0.1)**	4
Component Spacing	**P**	12
Hole Diameter	**D (± 0.1/-0)**	1.5
Hole Diameter	**D1 (min)**	1.5
Hole Position	**F (± 0.05)**	7.5
Compartment Depth	**K (max)**	6.5
Hole Spacing	**P1 (± 0.1)**	2

All dimensions are in mm.







REVISION HISTORY

Table 16. Revision History

Date	Revision	Description of Changes
Jul. 2004	1	- Current and voltage convention update. - “Configuration diagram (top view) & suggested connections for unused and n.c. pins” insertion. - 6 cm^2 Cu condition insertion in Thermal Data table. - V_{CC} - OUTPUT DIODE section update. - PROTECTIONS note insertion. - Revision History table insertion. - Disclaimers update.
Oct. 2004	2	- Minor text changes.